

150V, 200A, 3.7mΩ N-channel Power SGT MOSFET

JMSH1504NE

Features

- $\bullet \;\;$ Excellent $R_{DS(ON)}$ and Low Gate Charge
- 100% UIS TESTED
- 100% ΔVds TESTED
- Halogen-free; RoHS-compliant
- Pb-free plating

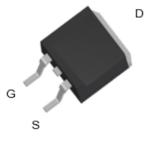
Applications

- Load Switch
- PWM Application
- Power Management

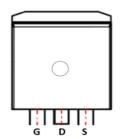
Product Summary

Parameters	Value	Unit
V_{DSS}	150	V
$V_{GS(th)_Typ}$	3.3	V
I _D (@V _{GS} =10V)	200	Α
$R_{DS(ON)_Typ}(@V_{GS}=10V$	3.7	mΩ

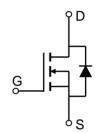








Pin Assignment



Schematic Diagram

Ordering Information

Device	Marking	MSL	Form	Package	Reel(pcs)	Per Carton (pcs)
JMSH1504NE	JMSH1504NE	3	Tape&Reel	TO-263-3L	800	4000

Absolute Maximum Ratings (@ T_C = 25°C unless otherwise specified)

Symbol	Parameter		Value	Unit	
V_{DS}	Drain-to-Source Voltage		150	V	
V_{GS}	Gate-to-Source Voltage		±20	V	
	I _D Continuous Drain Current		200	Λ	
I _D	Continuous Drain Current	$T_C = 100$ °C	141	Α	
I_{DM}	Pulsed Drain Current (1)		Refer to Fig.4	Α	
E _{AS}	Single Pulsed Avalanche Energy (2)		1309	mJ	
P _D	Power Dissipation	$T_C = 25^{\circ}C$	233	W	
' D	Fower Dissipation	$T_C = 100$ °C	93	VV	
T_{J}, T_{STG}	Junction & Storage Temperature Range		-55 to 150	°C	

Thermal Characteristics

Symbol	Parameter	Max	Unit
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (3)	28	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.5	C/ VV



Electrical Characteristics (T_J = 25°C unless otherwise specified)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Off Cha	racteristics					
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	150	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 120V, V_{GS} = 0V$	-	-	1.0	μА
I _{GSS}	Gate-Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	±100	nA
On Cha	racteristics					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.3	3.3	4.3	V
R _{DS(ON)}	Static Drain-Source ON-Resistance ⁽⁴⁾	$V_{GS} = 10V, I_D = 20A$	-	3.7	4.5	mΩ
Dynami	c Characteristics				•	
R_{g}	Gate Resistance	f = 1MHz	-	4.1	-	Ω
C _{iss}	Input Capacitance		6159	8622	11640	pF
C _{oss}	Output Capacitance	$V_{GS} = 0V, V_{DS} = 75V,$ f = 1MHz	551	772	1042	pF
C_{rss}	Reverse Transfer Capacitance	1 – 11/11/12	19	26	36	pF
Q_g	Total Gate Charge		90	125	169	nC
Q _{gs}	Gate Source Charge	$V_{GS} = 0 \text{ to } 10V$ $V_{DS} = 75V, I_{D} = 20A$	33	46	62	nC
Q_{gd}	Gate Drain("Miller") Charge	V DS = 70V, 1D = 20/1	23	32	43	nC
0 '/ 1 '						
	ng Characteristics	T		00	I	
t _{d(on)}	Turn-On DelayTime	-	-	32	-	ns
t _r	Turn-On Rise Time	$V_{GS} = 10V, V_{DD} = 75V$	-	60	-	ns
t _{d(off)}	Turn-Off DelayTime	$I_D = 20A, R_{GEN} = 3\Omega$	-	87	-	ns
t _f	Turn-Off Fall Time		-	48	-	ns
	iode Characteristics	_		ı	ı	
I _S	Maximum Continuous Body Diode Forward Current		-	-	200	Α
I _{SM}	ximum Pulsed Body Diode Forward Current		-	-	800	А
V_{SD}	Body Diode Forward Voltage	$V_{GS} = 0V, I_{S} = 20A$	-		1.2	V
trr	Body Diode Reverse Recovery Time	I _F = 20A, di/dt = 100A/us	80	111	150	ns
Qrr	Body Diode Reverse Recovery Charge	$\int_{0}^{\infty} f - 20A \operatorname{dival} = f - 20A \operatorname{ds}$	-	428	-	nC

Notes:

^{1.} Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.

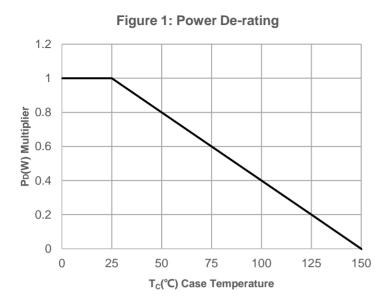
 $^{2.\;}E_{AS}\;condition:\;Starting\;T_J=25C,\;V_{DD}=75V,\;V_G=10V,\;R_G=25ohm,\;L=3mH,\;I_{AS}=29.54A,\;V_{DD}=0V\;during\;time\;in\;avalanche.$

^{3.} $R_{\theta JA}$ is measured with the device mounted on a 1inch² pad of 2oz copper FR4 PCB.

^{4.} Pulse Test: Pulse Width≤300μs, Duty Cycle≤0.5%.



Typical Performance Characteristics



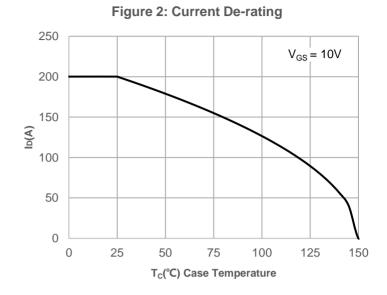
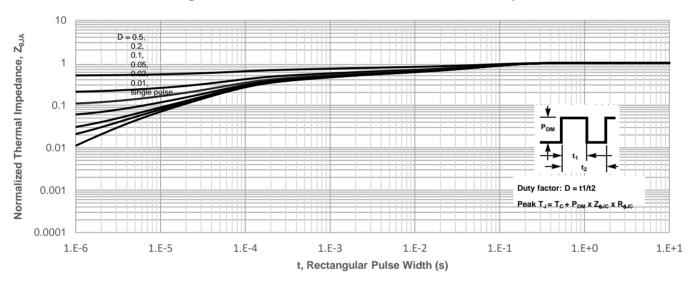
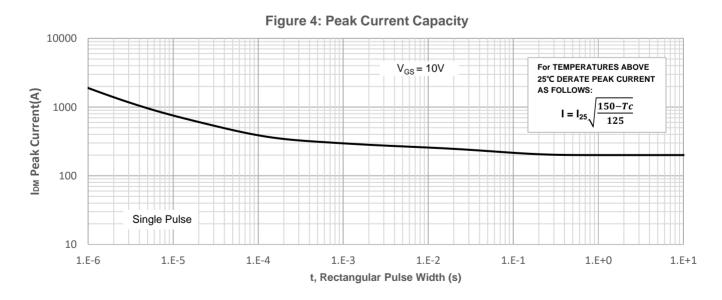


Figure 3: Normalized Maximum Transient Thermal Impedance







Typical Performance Characteristics

Figure 5: Output Characteristics

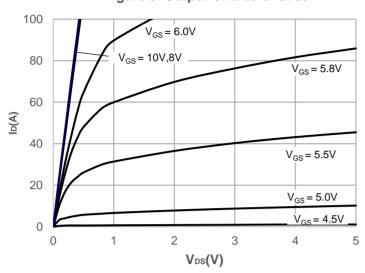


Figure 6: Typical Transfer Characteristics

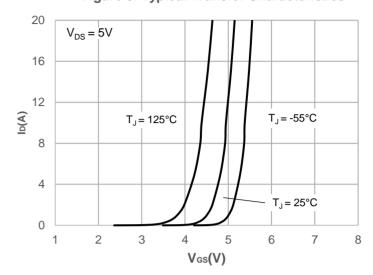


Figure 7: On-resistance vs. Drain Current

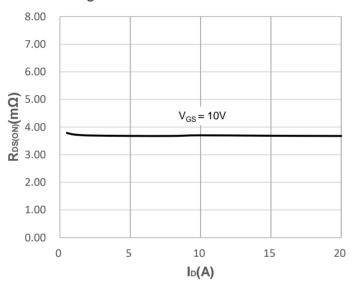


Figure 8: Body Diode Characteristics

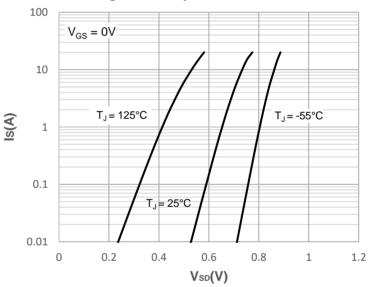


Figure 9: Gate Charge Characteristics

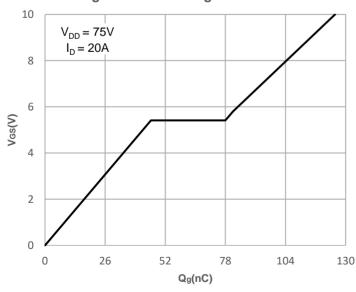
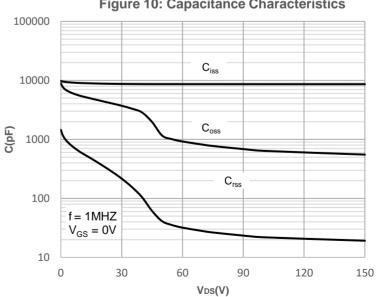


Figure 10: Capacitance Characteristics





Typical Performance Characteristics

Figure 11: Normalized Breakdown voltage vs. Junction Temperature

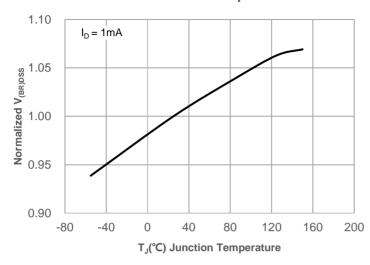


Figure 13: Normalized Threshold Voltage vs. Junction Temperature

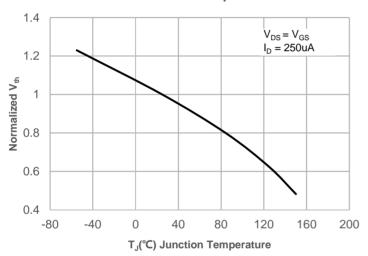


Figure 15: Maximum Safe Operating Area

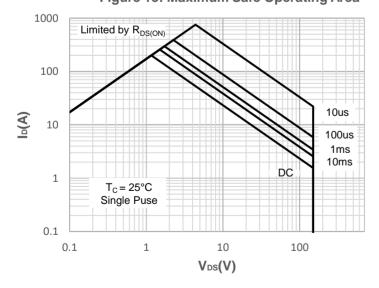
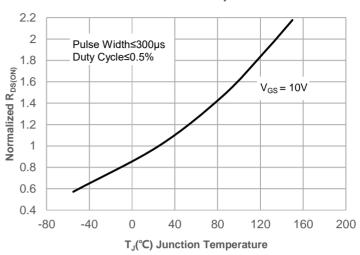
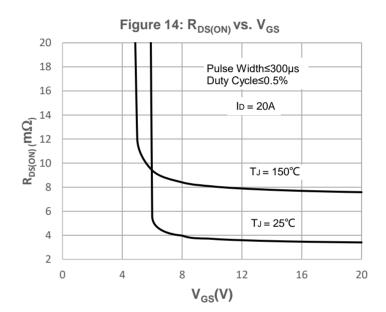


Figure 12: Normalized on Resistance vs. Junction Temperature







Test Circuit

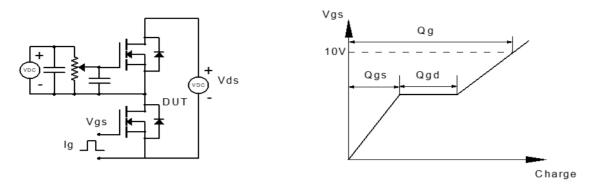


Figure 1: Gate Charge Test Circuit & Waveform

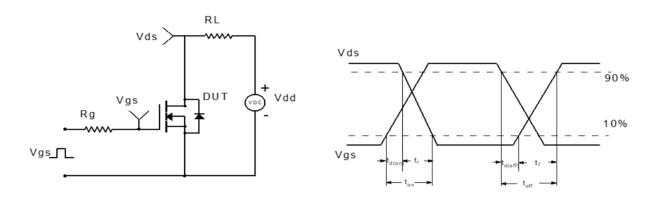


Figure 2: Resistive Switching Test Circuit & Waveform

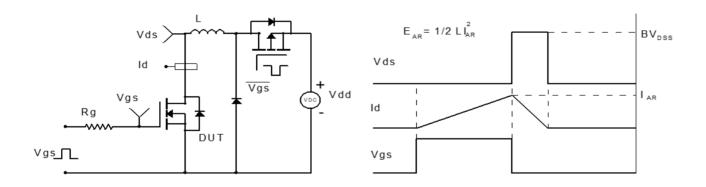


Figure 3: Unclamped Inductive Switching Test Circuit& Waveform

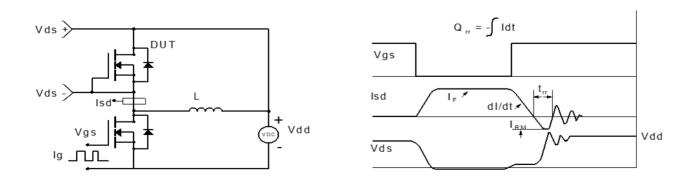
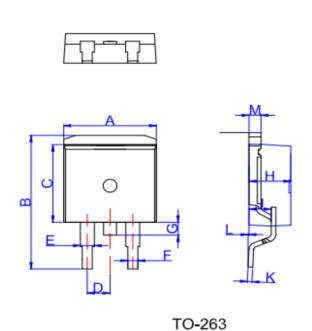


Figure 4: Diode Recovery Test Circuit & Waveform

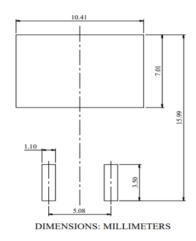


Package Mechanical Data(TO-263-3L)



			Dime	nsions		
Ref.	Millimeters			Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max.
Α	9.90		10.20	0.390		0.402
В	14.70		15.80	0.579		0.622
С	9.4		9.6	0.37		0.378
D		2.54			0.100	
E	1.20		1.40	0.047		0.055
F	0.75		0.85	0.029		0.033
G			1.75			0.069
Н	4.40		4.70	0.173		0.185
J	2.30		2.70	0.091		0.106
K	0.38		0.55	0.015		0.022
L	0	0.10	0.25	0	0.004	0.010
М	1.25		1.35	0.049		0.053

Recommended Footprint



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